Advances in Complex Cyberattack Detection

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Message from the Guest Editors

Dear Colleagues,

The aim of this Special Issue is to bring together leading academic scientists, researchers and scholars to exchange and share the most recent innovations, trends, and concerns, as well as practical challenges encountered and solutions adopted, in the field of complex cybersecurity threats.

Potential topics include—but are not limited to—the following:

1. Cyberattack detection, prediction, and association analysis;
2. Malware analysis and vulnerability detection using deep learning;
3. Malicious encrypted traffic detection;
4. Zero-day cyberattack detection using deep learning;
5. Adversarial attack and defense in cyberattacks;
6. The construction and reasoning of security knowledge graphs;
7. Cyber threat intelligence;
8. Research challenges in complex cyberattack detection;
9. Novel ideas, algorithms, models, frameworks, and systems for cyberattack detection.

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Special Issue

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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